

Materials List for:

## Electron Channeling Contrast Imaging for Rapid III-V Heteroepitaxial Characterization

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### Materials

Name	Company	Catalog Number	Comments
Sirion Field Emission SEM	FEI/Phillips	516113	Field emission SEM with beam voltage range of 200 V - 30 kV, equipped with a backscattered electron detector
Sample of Interest	Internally produced		Synthesized/grown in-house via MOCVD
PELCO SEMClip	Ted Pella, Inc.	16119-10	Reusable, non-adhesive SEM sample stub (adhesive attachment will also work)